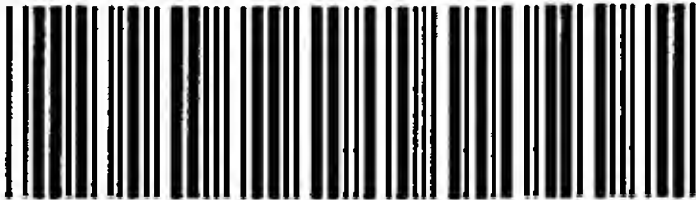


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/709,425	WANG ET AL.	
	Examiner	Art Unit	
	Mohamed Charioui	2857	

SEARCHED			
Class	Subclass	Date	Examiner
702	57-59, 64, 69, 117, 118, 119	12/1/2005	MC
702	120-123	12/1/2005	MC
702	183, 184	12/1/2005	MC
702	193	12/1/2005	MC
714	738,744	12/1/2005	MC
324	76.11	12/1/2005	MC
324	158.1	12/1/2005	MC
324	765	12/1/2005	MC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East: (latch\$up near test\$3)".ti" and "pin" and program\$6	12/1/2005	MC
East: (latch\$up near test\$3)".ti" and "pin" and program\$6	12/1/2005	MC
East: (test\$6 near chip) with current with ground	12/1/2005	MC
East: (test\$6 near pin) with current with measur\$6	12/1/2005	MC
East: "PMU" with pin with current	12/1/2005	MC